





GUANGDONG OPPO MOBILE TELECOMMUNICATIONS CORP., LTD.

For

Mobile Phone

Model Name:

OPPO R1001

Trade Name:

OPPO

Brand Name:

OPPO

FCC ID:

R9C-R1001

Standard:

47 CFR Part 15 Subpart B

Test date:

February 24, 2014 - March 14, 2014

Issue date:

March 14, 2014

By

Shenzhen Morlab Communications Technology Co., Ltd.

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Tested by Cai Junlong

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Date 2014.2.14

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Confidence Conf

Review by Wuzhangli

Wu Zhangli

(EMC Manager)

Date

2014.3.14

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	Change History				
Issue	Date	Reason for change			
1.0	March 14, 2014	First edition			

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1. GENERAL INFORMATION

1.1 EUT Description

EUT Type:	Mobile Phone		
Serial No:	(n.a., marked #1 by test site)		
Hardware Version:	213076		
Software Version:	R1001_11_140214		
Applicant:	GUANGDONG OPPO MOBILE TELECOMMUNICATIONS CORP., LTD.		
	NO.18 HAIBIN ROAD, WUSHA, CHANG'AN, DONGGUAN, GUANGDONG,		
	CHINA		
Manufacturer:	GUANGDONG OPPO MOBILE TELECOMMUNICATIONS CORP., LTD.		
	NO.18 HAIBIN ROAD, WUSHA, CHANG'AN, DONGGUAN, GUANGDONG,		
	CHINA		

Power supply:	Battery		
	Brand Name:	OPPO	
	Model No.:	BLT029	
	Serial No.:	(n.a. marked #1 by test site)	
	Capacitance:	1700mAh	
	Rated Voltage:	3.8V	
	Charge Limit:	4.35V	
Ancillary Equipment:	AC Adapter (Charger for Battery)		
	Brand Name:	OPPO	
	Model No.:	S01A22PP	
	Serial No.:	(n.a. marked #1 by test site)	
	Rated Input:	~ 100-240V, 150mA, 50/60Hz	
	Rated Output:	= 5V, 1000mA	

NOTE:

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- 1. The EUT is a Mobile Phone. It is equipped with a T-Flash card slot, a Micro-USB port which can be connected to the ancillary equipments e.g. the PC. It supports FM function.
- 2. Please refer to Annex A for the photographs of the EUT. For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.

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Report No.: SZ14020093E01

1.2 Test Standards and Results

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15(10-1-13 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result
1	15.107	Conducted Emission	PASS
2	15.109	Radiated Emission	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2009.

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1.3 Facilities and Accreditations

1.3.1 Facilities

Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L3572.

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All measurement facilities used to collect the measurement data are located at FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China 518101. The test site is constructed in conformance with the requirements of ANSI C63.4-2009 and CISPR Publication 22:2008; the FCC registration number is 695796.

1.3.2 Environmental Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 -106

1.3.3 Measurement Uncertainty

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The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB

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2. TEST CONDITIONS SETTING

2.1 Test Mode

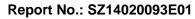
1	The first test mode (Data Transmission)			
	The EUT configuration of the emission tests is EUT + Battery + T-Flash Card + PC.			
	In this test mode, the EUT with a T-Flash Card embedded was connected to a PC via			
	the Micro-B USB port. During the measurement, the date is transmitting between the			
	PC and the T-Flash Card of the EUT.			
2	The second test mode (FM)			
	The EUT configuration of the emission tests is EUT + Battery + Charger.			
	During the measurement, the FM function was active.			
3	The third test mode (Standby)			
	The EUT configuration of the emission tests is EUT + Battery + Charger.			
	During the measurement, the EUT was charged by its adapter and turned on.			
Note	: All test modes are performed, only the worst case(Data Transmission) is recorded in this			
repor	rt.			

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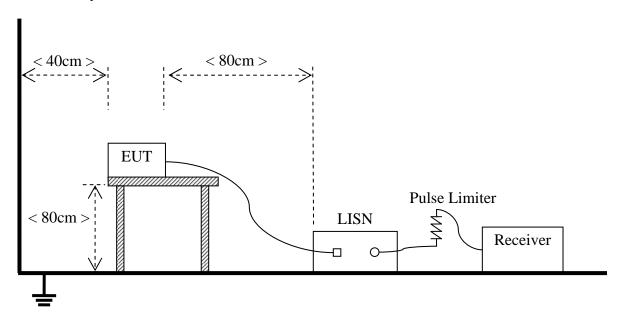




2.2 Test Setup and Equipments List

2.2.1 Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	12/11/2013	11/11/2014
EMC Analyzer	Agilent	E7405A	US44210471	12/05/2013	11/05/2014
LISN	Schwarzbeck	NSLK 8127	812744	12/05/2013	11/05/2014
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	12/05/2013	11/05/2014
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)

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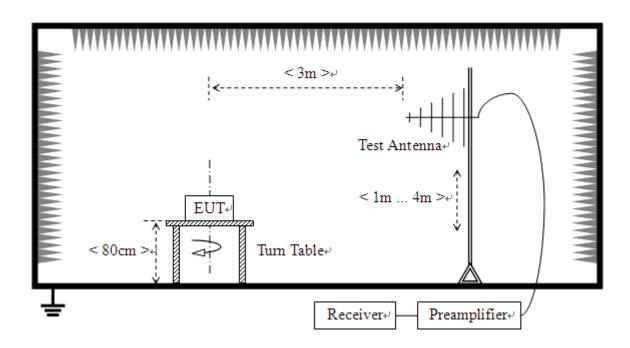




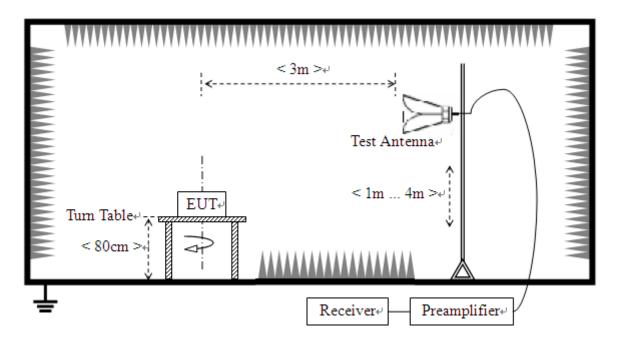
2.2.2 Radiated Emission

A. Test Setup:

1) For radiated emissions from 30MHz to1GHz



2) For radiated emissions above 1GHz



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table,

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and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

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Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
EMC Analyzer	Agilent	E7405A	US44210471	12/05/2013	11/05/2014
Semi-Anechoic	Albatross	9m*6m*6m	(n.a.)	12/05/2012	11/05/2014
Chamber					
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	12/05/2012	11/05/2014
Test Antenna - Horn	Schwarzbeck	BBHA 9120D	9120D-963	12/05/2012	11/05/2014
Test Antenna -Loop	Schwarzbeck	FMZB 1519	1519-022	12/05/2012	11/05/2014
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)

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3. 47 CFR PART 15B REQUIREMENTS

3.1 Conducted Emission

3.1.1 Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu\text{H}/50\Omega$ line impedance stabilization network (LISN).

Eroguanov rango (MUz)	Conducted Limit (dBµV)			
Frequency range (MHz)	Quasi-peak	Average		
0.15 - 0.50	66 to 56	56 to 46		
0.50 - 5	56	46		
5 - 30	60	50		

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

3.1.2 Test Description

See section 2.2.1 of this report.

3.1.3 Test Result

Web site: http://www.morlab.cn/

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

A. Test Plot and Suspicious Points:

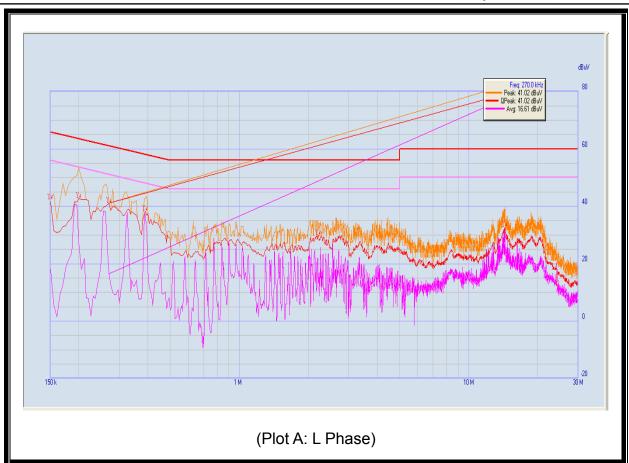
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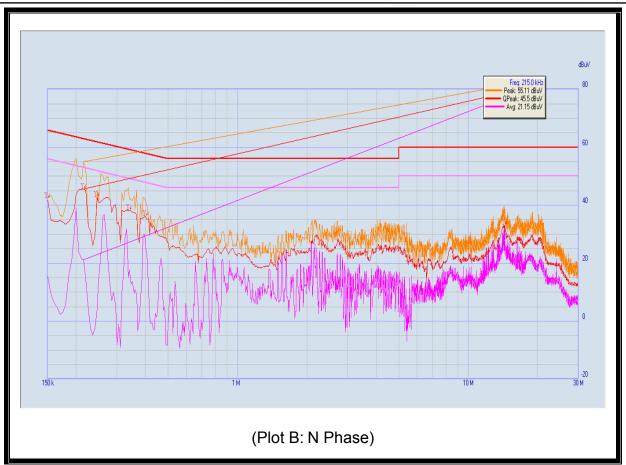


NO.	Fre. (MHz)	Emission Level (dBµV)		Limit (d	dΒμV)	Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	42.43	18.79	66.00	56.00		PASS
2	0.20	42.72	40.64	64.57	54.57		PASS
3	0.27	41.02	16.61	62.57	52.57	Lino	PASS
4	0.39	38.33	37.44	59.14	49.14	Line	PASS
5	2.215	29.63	25.14	56.00	46.00		PASS
6	14.34	32.11	31.46	60.00	50.00		PASS

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NO.	Fre. (MHz)	Emission Level (dBµV)		Limit (dBµV)	Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	42.43	15.34	66.00	56.00		PASS
2	0.215	45.50	21.15	64.14	54.14		PASS
3	0.245	42.73	12.58	63.29	53.29	Neutral	PASS
4	0.34	38.26	28.37	60.57	50.57	Neutrai	PASS
5	0.40	36.17	30.01	58.86	48.86		PASS
6	14.335	32.20	31.28	60.00	50.00		PASS

Test Result: PASS

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3.2 Radiated Emission

3.2.1 Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

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Frequency	Field Stre	ngth	Field Strength Limitation at 3m Measurement Dist			
range (MHz)	μV/m	Dist	(μV/m)	(dBµV/m)		
30.0 - 88.0	100	3m	100	20log 100		
88.0 - 216.0	150	3m	150	20log 150		
216.0 - 960.0	200	3m	200	20log 200		
Above 960.0	500	3m	500	20log 500		

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level(μV/m).
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * $(d2/d1)^{2}$.

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

3.2.2 Test Description

See section 2.2.2 of this report.

3.2.3 Frequency range of measurement

Highest frequency generated or used in the device is the highest speed of the processor, lowest frequency generated or used in the device is the lowest frequency of the oscillator. According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

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Frequency	Frequency generated or used in the device	Frequency range of radiated measurement in the report		
Highest	1.3GHz	6.5GHz		

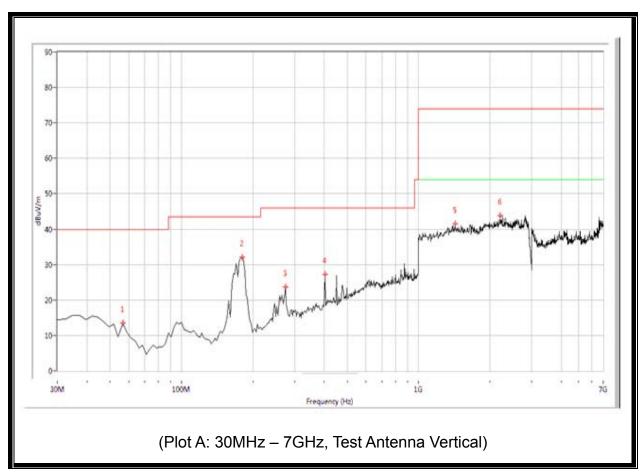
3.2.4 Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

A. Test Plots and Suspicious Points:



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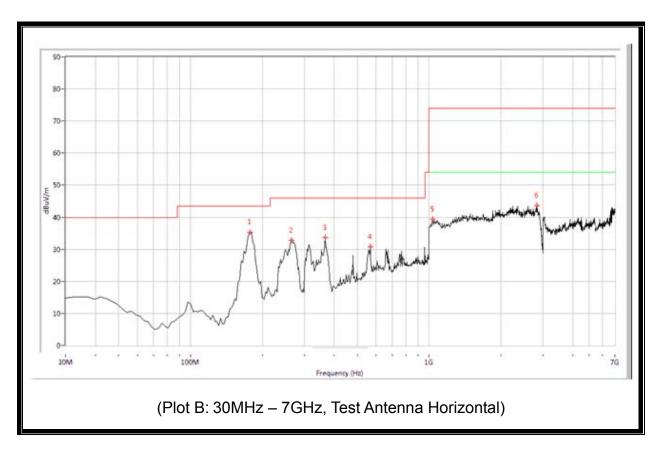
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NO.	Fre.	Pk	QP	AV	Limit-	Limit-	Limit-	Antenna	Verdict
	(MHz)				PK	QP	AV		
1	56.608	N.A	13.47	N.A	N.A	40.0	N.A	Vertical	Pass
2	179.975	N.A	32.07	N.A	N.A	43.5	N.A	Vertical	Pass
3	274.314	N.A	23.67	N.A	N.A	46.0	N.A	Vertical	Pass
4	402.519	N.A	27.33	N.A	N.A	46.0	N.A	Vertical	Pass
5	1423.940	41.52	N.A	35.82	74.0	N.A	54.0	Vertical	Pass
6	2211.970	43.83	N.A	36.45	74.0	N.A	54.0	Vertical	Pass



NO.	Fre.	Pk	QP	AV	Limit-	Limit-	Limit-	Antenna	Verdict
	(MHz)				PK	QP	AV		
1	177.556	N.A	35.27	N.A	N.A	43.5	N.A	Horizontal	Pass
2	264.638	N.A	32.83	N.A	N.A	46.0	N.A	Horizontal	Pass
3	366.234	N.A	33.75	N.A	N.A	46.0	N.A	Horizontal	Pass
4	567.007	N.A	30.80	N.A	N.A	46.0	N.A	Horizontal	Pass
5	1034.913	39.36	N.A	33.21	74.0	N.A	54.0	Horizontal	Pass
6	2820.449	43.60	N.A	35.96	74.0	N.A	54.0	Horizontal	Pass

Test Result: PASS

**END OF REPORT **

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